

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of: **Takashi FUJITA et al.**

Art Unit: **1797**

Application Number: **10/561,538**

Examiner: **Xiaoyun Xu**

Filed: **December 19, 2005**

Confirmation Number: **9367**

For: **SPECIFIC COMPONENT MEASURING METHOD BY SPECTRAL
MEASUREMENT**

Attorney Docket Number: **053362**
Customer Number: **38834**

RESPONSE UNDER 37 C.F.R. § 1.116
EXPEDITED PROCESSING REQUESTED

Mail Stop: AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

June 10, 2010

Sir:

This paper is filed in response to the Office Action dated March 3, 2010.

Remarks begin on page 2 of this paper.